

8-Bit Addressable Latch

ELECTRICALLY TESTED PER: MIL-M-35810/31603

The 54LS259 is a high-speed 8-Bit Addressable Latch designed for general purpose storage applications in digital systems. It is a multifunctional device capable of storing single line data in eight addressable latches, and also a 1-of-8 decoder and demultiplexer with active HIGH outputs. The device also incorporates an active LOW common Clear for resetting all latches, as well as, an active LOW Enable.

- · Serial-to-Parallel Conversion
- Eight Bits of Storage with Output of Each Bit Available
- · Random (Addressable) Data Entry
- Easily Expandable
- Common Clear

CONNECTION DIAGRAM

1	A	$\sqrt{v_{CC}}$	16
2	В	CLR:Č	15
3	С	Ē	14
4	Q ₀	D	13
5	01	a ₇	12
6	Q_2	\mathfrak{q}_6	11
7	03	Q_5	10
8	GND	Q_4	9

FUNCTIONAL DESCRIPTION

The 54LS259 has four modes of operation as shown in the mode selection table. In the addressable latch mode, data on the Data line (D) is written into the addressed latch. The addressed latch will follow the data input with all non-addressed latches remaining in their previous states. In the memory mode, all latches remain in their previous state and are unaffected by the Data or Address inputs.

In the one-of-eight decoding or demultiplexing mode, the addressed output will follow the state of the D input with all other inputs in the LOW state. In the clear mode all outputs are LOW and unaffected by the address and data inputs.

When operating the 54LS259 as an addressable latch, changing more than one bit of the address could impose a transient wrong address. Therefore, this should only be done while in the memory mode.

Military 54LS259



AVAILABLE AS:

1) JAN: JM35810/31603BXA

2) SMD: *

3) 883C: 54LS259/BXAJC

X = CASE OUTLINE AS FOLLOWS: PACKAGE: CEDIP: E CERFLAT: F

LCC: 2
*Call Factory for latest update

PIN ASSIGNMENTS

FUNCTION	DIL	FLATS	LCC	BURN-IN (CONDITION A
A	1	1	2	GND
В	2	2	3	GND
С	3	3	4	GND
Q_0	4	4	5	VCC
Q ₁	5	5	7	OPEN
Ω ₂	6	6	8	OPEN
Ω3	7	7	9	OPEN
GND	8	8	10	GND
04	9	9	12	OPEN
Q ₅	10	10	13	OPEN
Ω ₆	11	11	14	OPEN
07	12	12	15	OPEN
DATA (D)	13	13	17	VCC
ENABLE (E)	14	14	18	GND
CLR (C)	15	15	19	GND
Vcc	16	16	20	VCC

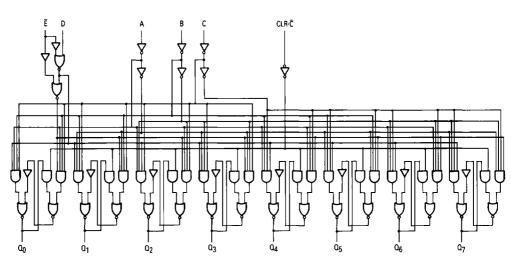
BURN-IN CONDITIONS: VCC = 5.0 V MIN/6.0 V MAX

MODE SELECTION							
Ē	Ē	MODE					
L H	H	Addressable Latch Memory					
L	L	Active HIGH Eight-Channel Demultiplexer					
Н	L	Clear					

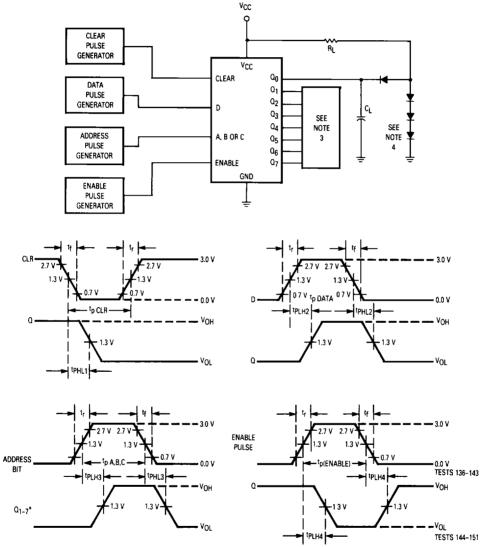
							TRUT	TABLE	•					
	Present Output States													
C	Ē	D	Α	В	С	α ₀	Q ₁	Ω2	03	04	Ω5	Ω6	Ω7	MODE
L	н	Х	X	X	L	L	L	L	L	L	L	L	L	Clear
L	L	Ł	L	L	L	L	L	L	L	L	L	L	L	Demultiplex
L	L	н	Ļ	L	L	H	L	L	L	L	L	L	L	
L	L	L	Н	L	L	L	L	L	L	L	L	L	L	
Ł	Ł	Н	Н	L	L	L	н	L	L	L	L	L	L	
•	•	•		•				•						
•	•	•		•				•						
:	•	•		•				•						
:	·	:		•				•						
Ĺ	Ĺ	Н	н	H	н	L	L	L	L	L	L	L	н	
н	Н	Х	Х	x	х	Q _{N-1}								Memory
Н	1	ı	L	L	L	L	Q _{N-1}	Q _{N-1}	Q _{N-1} -				>	Addressable
Н	L	н	Ł	L	L	н	Q_{N-1}	Q _{N-1} -						Latch
н	L	L	н	L	L	Q _{N-1}	L	QN-1 -						-
н	L	н	Н	L	L	Q _{N-1}	н	Q _{N-1}						4
•	•	•						•						
•	•	•						•						
•	•	•						•						
•	•	•						•						
•	•	•						•						
Н	L	L	н	Н	H	Q _{N-1} -						► Q _{N-1}	L	
н	L	н	н	н	н	Q _{N-1} -						►Q _{N-1}	Н	

- X = Don't Care
 L = LOW Voltage Level
 H = HIGH Voltage Level
 Q_{N-1} = Previous Output State

LOGIC DIAGRAM



AC TEST CIRCUIT AND WAVEFORMS



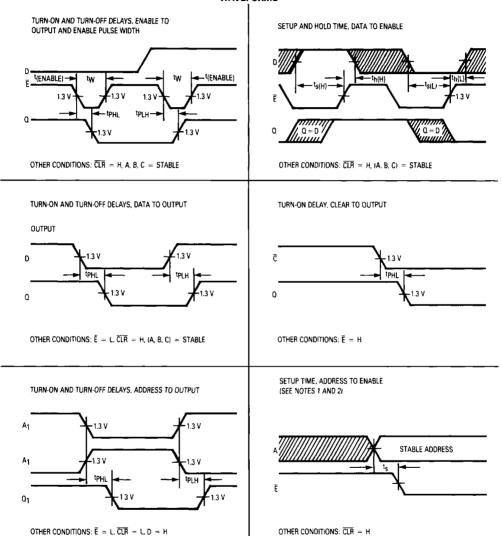
*For Q₀ output, waveform is inverted and tp_{LH3} and tp_{HL3} are interchanged.

NOTES:

- NOTES: $1. R_{\parallel} = 2.0 \, \mathrm{k}\Omega \pm 5.0\%$. 2. $C_{\parallel} = 50 \, \mathrm{pF} \pm 10\%$ including probe and jig capacitance. 3. All loads are the same as the Q_0 load. 4. All diodes are 1N3064 or equivalent.

- 5. The clear, enable, data and address pulse generators have the In e clear, enable, data and address pulse generators have the following characteristics: ty < 15 ns, ty < 6.0 ns, tp < 30 ns, PRR ≤ 1.0 MHz, tp[ENABLE] = 17 ns, tp(DATA) = 22 ns, tp(ADDRESS) = 47 ns, tsetup = 17 ns, thOLD = 15 ns.
 ferminal conditions (pins not designated may be high ≥ 2.0 V, low ≤ 0.7 V, or open).

WAVEFORMS



NOTES:

- The Address to Enable Setup Time is the time before the HIGH-to-LOW Enable transition that the Address must be stable so that the correct latch is addressed and the other latches are not affected.
- The shaded areas indicate when the inputs are permitted to change for predictable output performance.

<u>'</u>	Parameter			Lin	nits		Units	Test Condition (Unless Otherwise Specified)	
		+2	5°C	+ 125℃		-55°C			
	Static Parameters:	Subgroup 1		Subgroup 2		Subgroup 3			
		Min	Max	Min	Max	Min	Max	1	
∨он	Logical "1" Output Voltage	2.5		2.5		2.5	•	٧	V _{CC} = 4.5 V, I _{OH} = -0.4 mA, V _{IH} = 2.0 V, V _{IL} = 0.7 V, D & CLR = 2.0 V, E = (See Note 1).
V _{OL}	Logical "0" Output Voltage		0.4		0.4		0.4	٧	$ \begin{array}{l} {\rm V_{CC}} = 4.5 \; {\rm V, \; I_{OL}} = 4.0 \; {\rm mA, \; V_{IL}} = 0.7 \; {\rm V, } \\ {\rm V_{IH}} = 2.0 \; {\rm V, \; CLR} = 2.0 \; {\rm V, \; D} = 0.7 \; {\rm V, } \\ {\rm E} = ({\rm See \; Note \; 1}). \\ \end{array} $
V _{IC}	Input Clamping Voltage		- 1.5					٧	$V_{CC} = 4.5 \text{ V}$, $I_{IN} = -18 \text{ mA}$, other inputs are GND.
ll L	Logical "0" Input Current	-0.12	-0.36	-0.12	-0.36	-0.12	- 0.36	mA	V _{CC} = 5.5 V, V _{IN} = 0.4 V, other inputs are open.
lıL	Logical "0" Input Current	-0.005	-0.72	- 0.005	-0.72	-0.005	-0.72	mA	V _{CC} = 5.5 V, V _{IN(E)} = 0.4 V, other inputs are open.
Ιн	Logical "1" Input Current		20		20		20	μΑ	V _{CC} = 5.5 V, V _{IH} = 2.7 V.
Інн	Logical "1" Input Current		100		100		100	μΑ	V _{CC} = 5.5 V, V _{IHH} = 5.5 V.
los	Output Short Circuit Current	- 15	- 100	- 15	- 100	- 100	- 15	mA	V _{CC} = 5.5 V, V _{IN} = 5.5 V or GND, D & CLR = 5.0 V, E = GND, V _{OUT} = GND.
lcc	Power Supply Current Off		36		36		36	mA	V _{CC} = 5.5 V, V _{IN} = GND (all inputs).
VIH	Logical "1" Input Voltage	2.0		2.0		2.0		٧	V _{CC} = 4.5 V.
VIL	Logical "0" Input Voltage		0.7		0.7		0.7	٧	V _{CC} = 4.5 V.
		Subgr	oup 7	Subgro	up 8A	Subgroup 8B			
	Functional Tests								per Truth Table with V _{CC} = 5.0 V, V _{INL} = 0.4, V _{INH} = 2.5 V.

NOTE:
1. Apply a 3.0 V, 0 V, 3.0 V momentary pulse 500 ns minimum prior to measurement.

Symbol	Parameter	Limits							Test Condition (Unless Otherwise Specified)
		+ 2	5°C	+ 125℃		55°C			
	Static Parameters:	Subgroup 9		Subgroup 10		Subgroup 11		1	
	rarameters.	Min	Max	Min	Max	Min	Max		
[†] PHL1 [†] PHL1	Propagation Delay CLR to Q _n	3.0	32 27	3.0	42 37	3.0	42 37	ns	$V_{CC} = 5.0 \text{ V, } C_L = 50 \text{ pF, } R_L = 2.0 \text{ k}\Omega.$ $V_{CC} = 5.0 \text{ V, } C_L = 15 \text{ pF.}$
[†] PHL2 [†] PHL2	Propagation Delay D to Q _n	3.0	26 21	3.0	34 29	3.0	34 29	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_L = 2.0 \text{ k}\Omega.$ $V_{CC} = 5.0 \text{ V}, C_L = 15 \text{ pF}.$
^t PLH2 ^t PLH2	Propagation Delay D to Q _n	3.0	37 32	3.0	48 43	3.0	48 43	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_L = 2.0 \text{ k}\Omega.$ $V_{CC} = 5.0 \text{ V}, C_L = 15 \text{ pF}.$
[†] PHL3 [†] PHL3	Propagation Delay A, B, C to Q _n	3.0	34 29	3.0	44 39	3.0	44 39	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_L = 2.0 \text{ k}\Omega.$ $V_{CC} = 5.0 \text{ V}, C_L = 15 \text{ pF}.$
^t PLH3 ^t PLH3	Propagation Delay A, B, C to Q _n	3.0	43 38	3.0	56 51	3.0	56 51	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_L = 2.0 \text{ k}\Omega.$ $V_{CC} = 5.0 \text{ V}, C_L = 15 \text{ pF}.$
^t PHL4 ^t PHL4	Propagation Delay E to Q _n	3.0	29 24	3.0	38 33	3.0	38 33	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_L = 2.0 \text{ k}\Omega.$ $V_{CC} = 5.0 \text{ V}, C_L = 15 \text{ pF}.$
^t PLH4 ^t PLH4	Propagation Delay E to Q _n	3.0	39 35	3.0	52 47	3.0	52 47	ns	$V_{CC} = 5.0 \text{ V}, C_L = 50 \text{ pF}, R_L = 2.0 \text{ k}\Omega.$ $V_{CC} = 5.0 \text{ V}, C_L = 15 \text{ pF}.$